

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/658,857	<b>Applicant(s)/Patent under Reexamination</b> KRUPKE, WILLIAM F.
	<b>Examiner</b> Leith A. Al-Nazer	<b>Art Unit</b> 2821

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner